Refine Search

Search Results -

. Terms	Documents
semiconductor and (nanoscale same roughness)	0

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Search History

DATE: Wednesday, February 16, 2005 Printable Copy Create Case

<u>Set Name Query</u>	<u>Hit Cour</u>	<u>ıt Set</u>	. Name
side by side		res	sult set
DB=JPAB; PLUR=YES; OP=ADJ			
<u>L7</u> semiconductor and (nanoscale sam	ne roughness)	0	<u>L7</u>
DB=EPAB; PLUR=YES; OP=ADJ			
<u>L6</u> semiconductor and (nanoscale sam	ne roughness)	0	<u>L6</u>
DB=USPT; PLUR=YES; OP=ADJ			
<u>L5</u> semiconductor and (nanoscale sam	ne roughness) 2	.4	<u>L5</u>
DB=PGPB; PLUR=YES; OP=ADJ			
<u>L4</u> semiconductor and (nanoscale sam	ne roughness) 2	.9	<u>L4</u>
DB=TDBD; PLUR=YES; OP=ADJ			
<u>L3</u> semiconductor and (nanoscale sam	ie roughness)	1	<u>L3</u>
DB=DWPI; PLUR=YES; OP=ADJ			
<u>L2</u> semiconductor and (nanoscale sam	ie roughness)	1	<u>L2</u>
<u>L1</u> 6417060.pn.		1	<u>L1</u>

END OF SEARCH HISTORY